

## 6<sup>th</sup> High Level Expert Meeting 2013 Asphere Metrology

## **Detailed Programme**

1st Day	Wednesday, 13 November 2013 / Morning Chair: Dr. Michael Schulz; PTB; Germany	1s Da	
9:00	Registration	12:5	
10:00	Conference Opening and Overview Prof. DrIng. Frank Löffler; CC UPOB e.V.; Germany	13:5	50
10:10	General Information on Topic Comparability Dr. Michael Schulz; PTB; Germany	14:2	20
	Session – Interferometry		
10:20	Recent Developments in Subaperture Stitching Interferometry of Aspheres and Free-Forms; Dr. Andrew Kulawiec; QED; USA	14:5	
10:50	Comparing Measurement Results: The Radius Issue Christoph Pruss; University Stuttgart ITO; Germany	15:4	
11:20	Coffee Break and Interesting Table Top Presentations	15.4	ŧU
	Session – Single Point Measurement	16:1	10
11:50	Recent Technology for Asphere and Free-Form Measurement by UA3P; Keishi Kubo; Panasonic Corporation; Japan	16:4	
12:20	Tactile and Contactless Measurement of an Optical Surface; Roland Maurer; TH Deggendorf; Germany	17:1	
12:50	Lunch Break and Interesting Table Top Presentations		
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1st Day	Wednesday, 13 November 2013 / Afternoon Chair: Gunter Schneider; Schneider GmbH & Co. KG; Germany
12:50	Lunch Break and Interesting Table Top Presentations
13:50	Measurement Applications for Ultra-Precision 3D Coordinate Metrology; Michiel Baas; IBS Precision Engineering; The Netherlands
14:20	Manufacturing and Measurement of Aspheres, Acylinders and Free-Form Optics; Dr. Georg Böhm; IOM; Germany
14:50	Measurement of Non-Standard Aspheres and Discontinuous Optics; Dr. Gernot Berger; Luphos GmbH; Germany
15:15	Coffee Break and Interesting Table Top Presentations
15:40	Parallel Measurement on Free-Form Optics with Optical Surfaces on Both Sides; Dr. Michael Quinten; Fries Research & Technology GmbH; Germany
16:10	Precision Measurement of Large Optical Surfaces Prof. Dr. Engelbert Hofbauer; TH Deggendorf; Germany
16:40	Tactile Probe Systems in Comparison with Optical Point Sensors for Measuring Optical Components Dr. Andreas Beutler; Mahr GmbH; Germany
17:10	Closing

19:00 Conference Dinner





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2nd Day	Thursday, 14 November 2013 / Morning Chair: Dr. Klaus F. Beckstette; Carl Zeiss Jena GmbH; Germany	2r Da
		12
9:00	Opening	
	Session – Deflectrometry / Raytracing	10
9:05	Measurement of Ultra Precise Aspheric Mirrors Dr. Frank Siewert; Helmholtz Zentrum Berlin; Germany	13:
9:35	Areal Absolute Form Measurement of Optical Surfaces using Phase Measuring Deflectometry and Shearing Interferometry; Marc Sandner; BIAS - Bremen Institute for Applied Beam Technology; Germany	14: 14:
10:05	Quantitative Deflectometry Challenges Interferometry Evelyn Olesch; University Erlangen-Nuermberg; Germany	14:
10:35	Coffee Break and Interesting Table Top Presentations	
	Session – CGH	
11:05	Testing High NA Cylinder Surfaces Using Special CGHs, Called Diffractive Transmission Cylinders (DTC) Dr. Frank Weidner; DIOPTIC GmbH; Germany	
11:35	Metrology of High Precision Free-Form Mirrors with Advanced Computer-Generated-Holograms Matthias Beier; Fraunhofer IOF; Germany	
12:05	Calibration Methods to Increase the Measurement Precision of Interferometric Asphere Testing Using CGHs Dr. Frank Weidner; DIOPTIC GmbH; Germany	

2nd Day	Thursday, 14 November 2013 / Afternoon Chair: Dr. Axel Schindler; NTG GmbH; Germany
12:35	Lunch Break and Interesting Table Top Presentations
	Session – Standardization / Others
13:35	Capabilities of Ion Beam Figuring Technology for Asphere Manufacturing; Dr. David Schäfer; NTG GmbH & Co. KG; Germany
14:05	Development of Aspherical Standard Specimens Gernot Blobel; PTB; Germany
14:35	Summary Dr. Michael Schulz; PTB; Germany
14:55	Conference Closing

